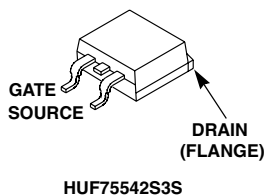
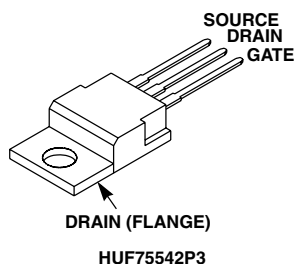
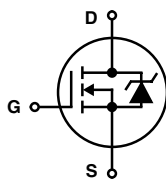


**75A, 80V, 0.014 Ohm, N-Channel,
UltraFET Power MOSFETs**
Packaging

JEDEC TO-220AB

JEDEC TO-263AB


Symbol

Features

- Ultra Low On-Resistance
 - $r_{DS(ON)} = 0.014\Omega$, $V_{GS} = 10V$
- Simulation Models
 - Temperature Compensated PSPICE® and SABER™ Electrical Models
 - Spice and SABER Thermal Impedance Models
 - www.intersil.com
- Peak Current vs Pulse Width Curve
- UIS Rating Curve

Ordering Information

PART NUMBER	PACKAGE	BRAND
HUF75542P3	TO-220AB	75542P
HUF75542S3S	TO-263AB	75542S

NOTE: When ordering, use the entire part number. Add the suffix T to obtain the variant in tape and reel, e.g., HUF75542S3ST.

Absolute Maximum Ratings $T_C = 25^\circ\text{C}$, Unless Otherwise Specified

	HUF75542P3, HUF75542S3S	UNITS
Drain to Source Voltage (Note 1)	V_{DS} 80	V
Drain to Gate Voltage ($R_{GS} = 20k\Omega$) (Note 1)	V_{DGR} 80	V
Gate to Source Voltage	V_{GS} ± 20	V
Drain Current		
Continuous ($T_C = 25^\circ\text{C}$, $V_{GS} = 10V$) (Figure 2)	I_D 75	A
Continuous ($T_C = 100^\circ\text{C}$, $V_{GS} = 10V$) (Figure 2)	I_D 58	A
Pulsed Drain Current	I_{DM} Figure 4	
Pulsed Avalanche Rating	UIS Figures 6, 14, 15	
Power Dissipation	P_D 230	W
Derate Above 25°C	1.54	W/ $^\circ\text{C}$
Operating and Storage Temperature	T_J, T_{STG} -55 to 175	$^\circ\text{C}$
Maximum Temperature for Soldering		
Leads at 0.063in (1.6mm) from Case for 10s.	T_L 300	$^\circ\text{C}$
Package Body for 10s, See Techbrief TB334	T_{pkg} 260	$^\circ\text{C}$

NOTE:

1. $T_J = 25^\circ\text{C}$ to 150°C .

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

Product reliability information can be found at <http://www.mtp.intersil.com/reliability.html>

For severe environments, see our Automotive HUFA series.

All Intersil semiconductor products are manufactured, assembled and tested under ISO9000 and QS9000 quality systems certification.

HUF75542P3, HUF75542S3S

Electrical Specifications T_C = 25°C, Unless Otherwise Specified

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNITS	
OFF STATE SPECIFICATIONS							
Drain to Source Breakdown Voltage	BV _{DSS}	I _D = 250μA, V _{GS} = 0V (Figure 11)	80	-	-	V	
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 75V, V _{GS} = 0V	-	-	1	μA	
		V _{DS} = 70V, V _{GS} = 0V, T _C = 150°C	-	-	250	μA	
Gate to Source Leakage Current	I _{GSS}	V _{GS} = ±20V	-	-	±100	nA	
ON STATE SPECIFICATIONS							
Gate to Source Threshold Voltage	V _{GS(TH)}	V _{GS} = V _{DS} , I _D = 250μA (Figure 10)	2	-	4	V	
Drain to Source On Resistance	r _{DS(ON)}	I _D = 75A, V _{GS} = 10V (Figure 9)	-	0.012	0.014	Ω	
THERMAL SPECIFICATIONS							
Thermal Resistance Junction to Case	R _{θJC}	TO-220 and TO-263	-	-	0.65	°C/W	
Thermal Resistance Junction to Ambient	R _{θJA}		-	-	62	°C/W	
SWITCHING SPECIFICATIONS (V _{GS} = 10V)							
Turn-On Time	t _{ON}	V _{DD} = 40V, I _D = 75A V _{GS} = 10V, R _{GS} = 3.9Ω (Figures 18, 19)	-	-	195	ns	
Turn-On Delay Time	t _{d(ON)}		-	12.5	-	ns	
Rise Time	t _r		-	117	-	ns	
Turn-Off Delay Time	t _{d(OFF)}		-	50	-	ns	
Fall Time	t _f		-	80	-	ns	
Turn-Off Time	t _{OFF}		-	-	195	ns	
GATE CHARGE SPECIFICATIONS							
Total Gate Charge	Q _{g(TOT)}	V _{GS} = 0V to 20V	V _{DD} = 40V, I _D = 75A, I _{g(REF)} = 1.0mA (Figures 13, 16, 17)	-	150	180	nC
Gate Charge at 10V	Q _{g(10)}	V _{GS} = 0V to 10V		-	80	96	nC
Threshold Gate Charge	Q _{g(TH)}	V _{GS} = 0V to 2V		-	5.7	7	nC
Gate to Source Gate Charge	Q _{gs}			-	15	-	nC
Gate to Drain "Miller" Charge	Q _{gd}			-	33	-	nC
CAPACITANCE SPECIFICATIONS							
Input Capacitance	C _{ISS}	V _{DS} = 25V, V _{GS} = 0V, f = 1MHz (Figure 12)	-	2750	-	pF	
Output Capacitance	C _{OSS}		-	700	-	pF	
Reverse Transfer Capacitance	C _{RSS}		-	250	-	pF	

Source to Drain Diode Specifications

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNITS
Source to Drain Diode Voltage	V _{SD}	I _{SD} = 75A	-	-	1.25	V
		I _{SD} = 37.5A	-	-	1.00	V
Reverse Recovery Time	t _{rr}	I _{SD} = 75A, dI _{SD} /dt = 100A/μs	-	-	102	ns
Reverse Recovered Charge	Q _{RR}	I _{SD} = 75A, dI _{SD} /dt = 100A/μs	-	-	255	nC

Typical Performance Curves

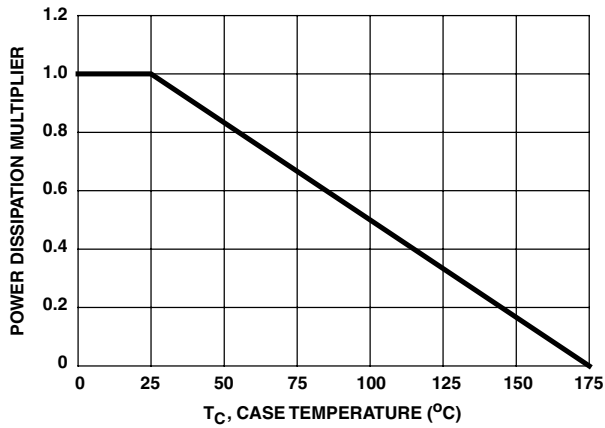


FIGURE 1. NORMALIZED POWER DISSIPATION vs CASE TEMPERATURE

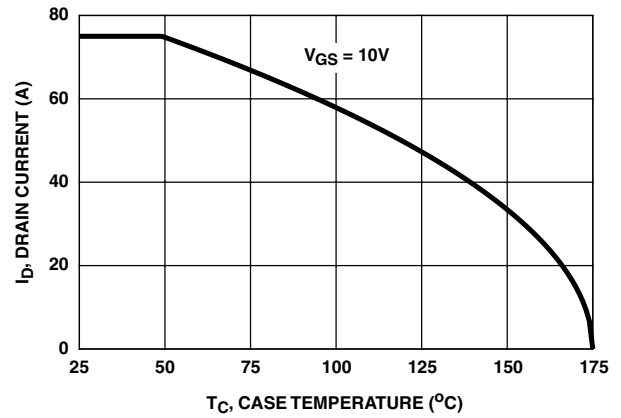


FIGURE 2. MAXIMUM CONTINUOUS DRAIN CURRENT vs CASE TEMPERATURE

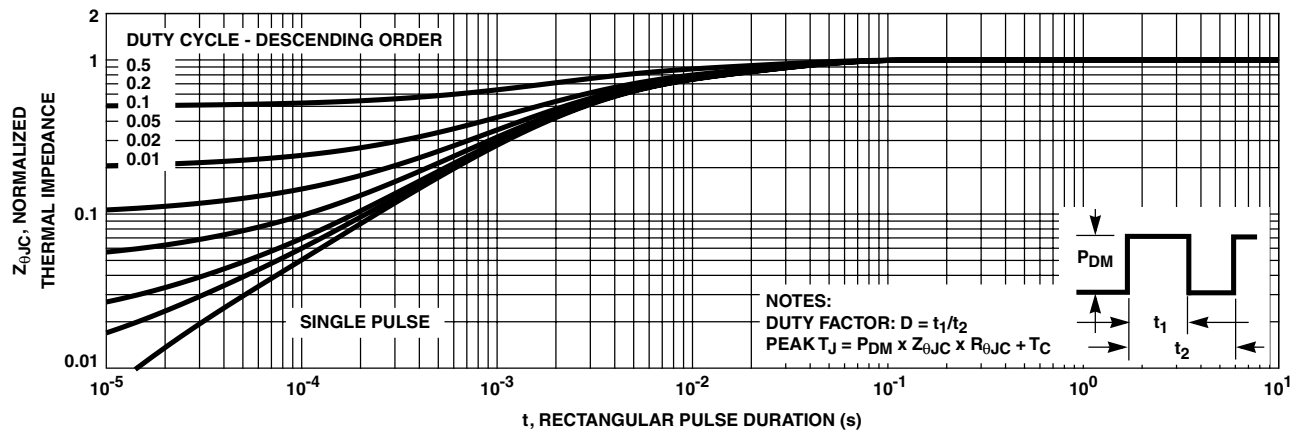


FIGURE 3. NORMALIZED MAXIMUM TRANSIENT THERMAL IMPEDANCE

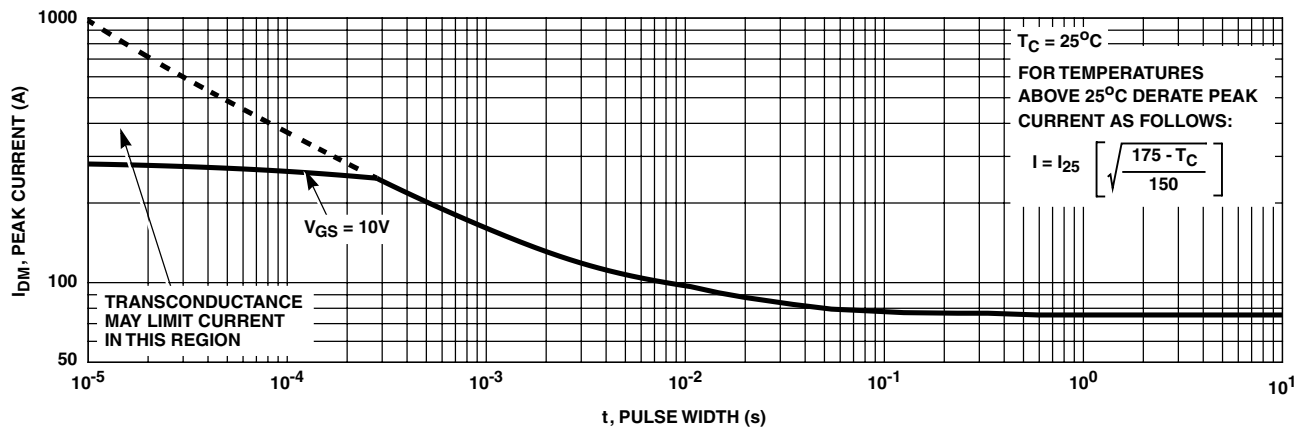


FIGURE 4. PEAK CURRENT CAPABILITY

Typical Performance Curves (Continued)

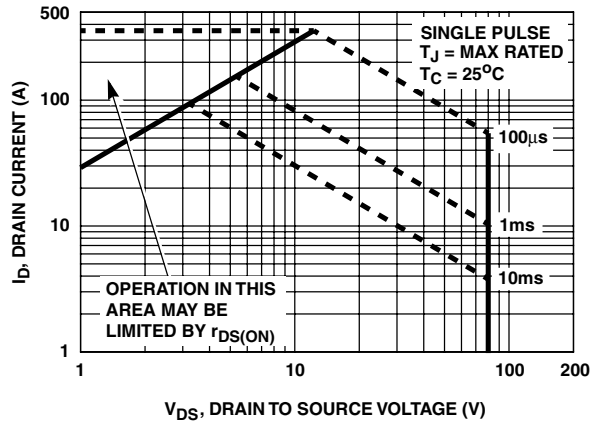
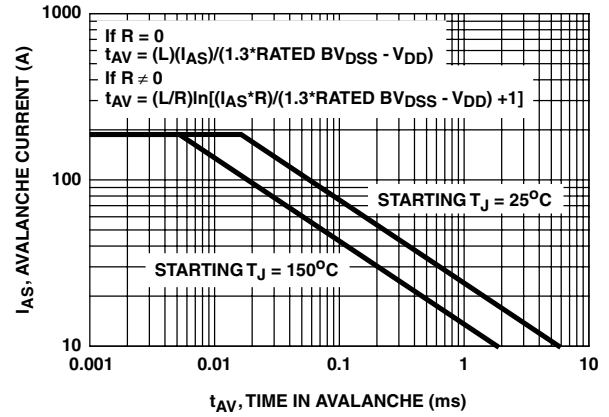


FIGURE 5. FORWARD BIAS SAFE OPERATING AREA



NOTE: Refer to Intersil Application Notes AN9321 and AN9322.

FIGURE 6. UNCLAMPED INDUCTIVE SWITCHING CAPABILITY

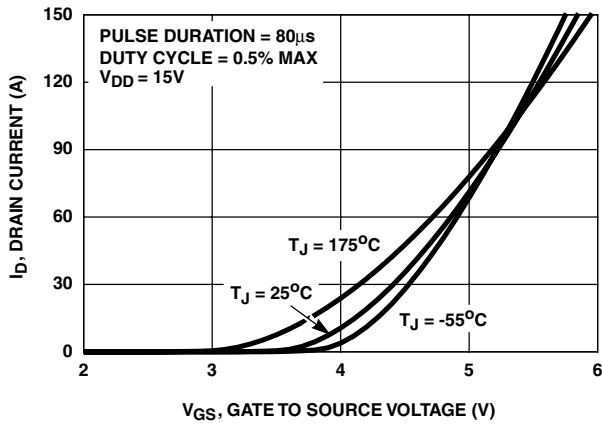


FIGURE 7. TRANSFER CHARACTERISTICS

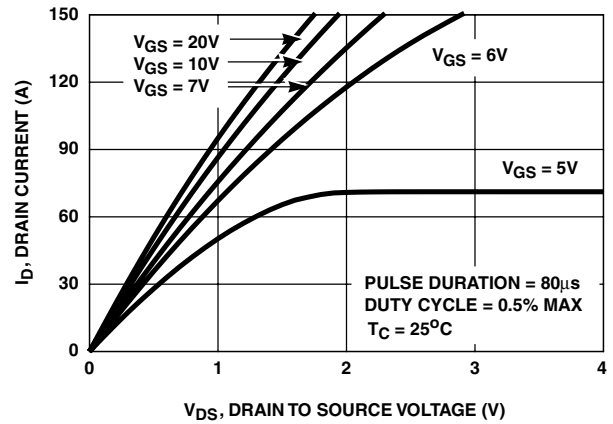


FIGURE 8. SATURATION CHARACTERISTICS

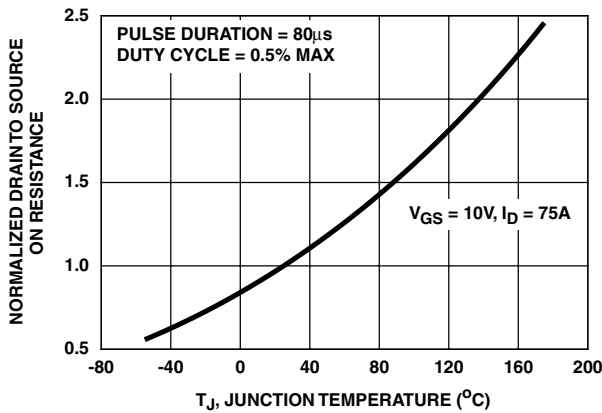


FIGURE 9. NORMALIZED DRAIN TO SOURCE ON RESISTANCE vs JUNCTION TEMPERATURE

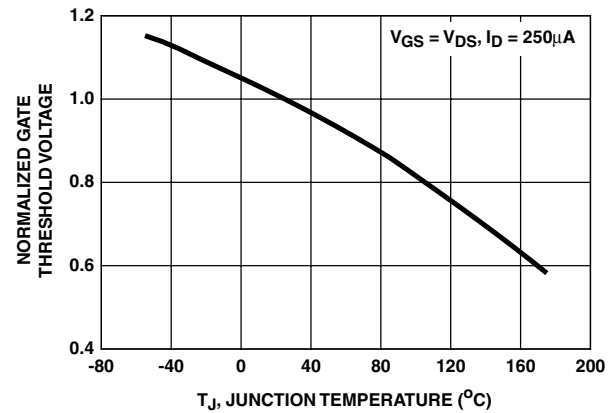


FIGURE 10. NORMALIZED GATE THRESHOLD VOLTAGE vs JUNCTION TEMPERATURE

Typical Performance Curves (Continued)

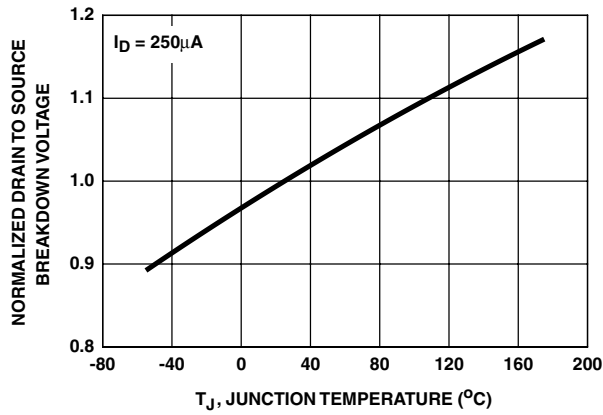


FIGURE 11. NORMALIZED DRAIN TO SOURCE BREAKDOWN VOLTAGE vs JUNCTION TEMPERATURE

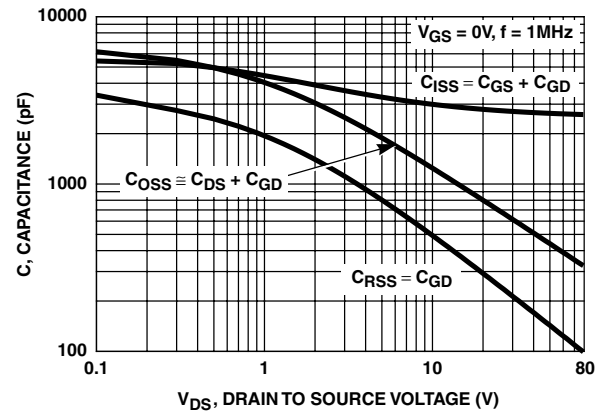
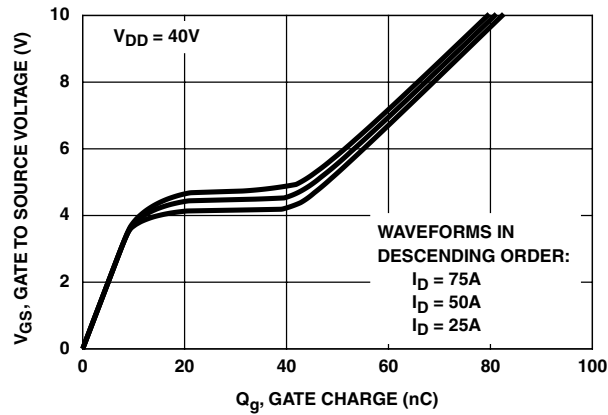


FIGURE 12. CAPACITANCE vs DRAIN TO SOURCE VOLTAGE



NOTE: Refer to Intersil Application Notes AN7254 and AN7260.

FIGURE 13. GATE CHARGE WAVEFORMS FOR CONSTANT GATE CURRENT

Test Circuits and Waveforms

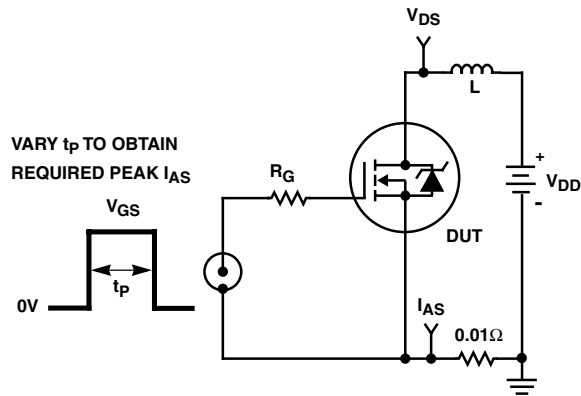


FIGURE 14. UNCLAMPED ENERGY TEST CIRCUIT

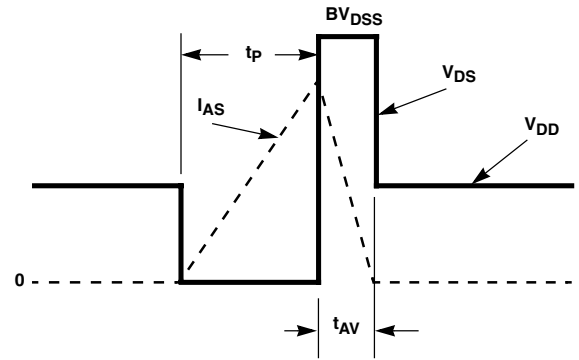


FIGURE 15. UNCLAMPED ENERGY WAVEFORMS

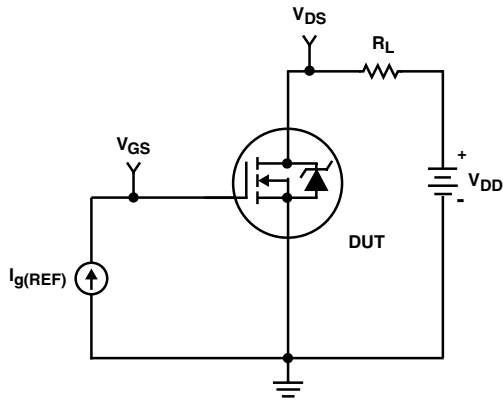


FIGURE 16. GATE CHARGE TEST CIRCUIT

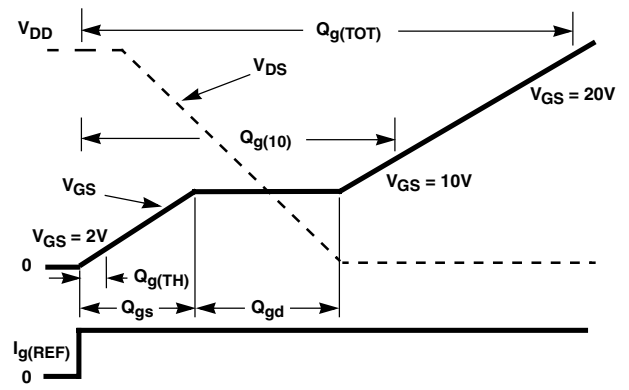


FIGURE 17. GATE CHARGE WAVEFORMS

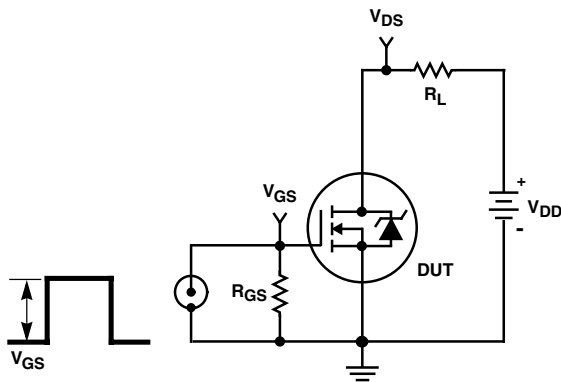


FIGURE 18. SWITCHING TIME TEST CIRCUIT

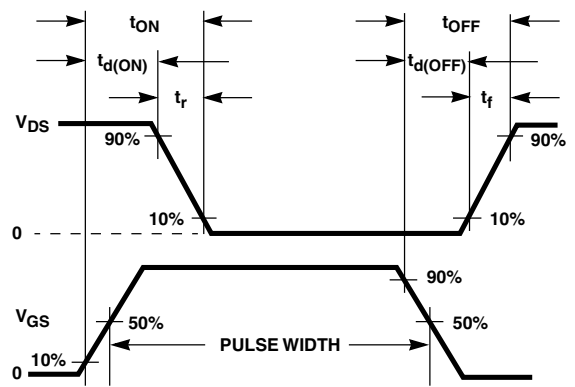
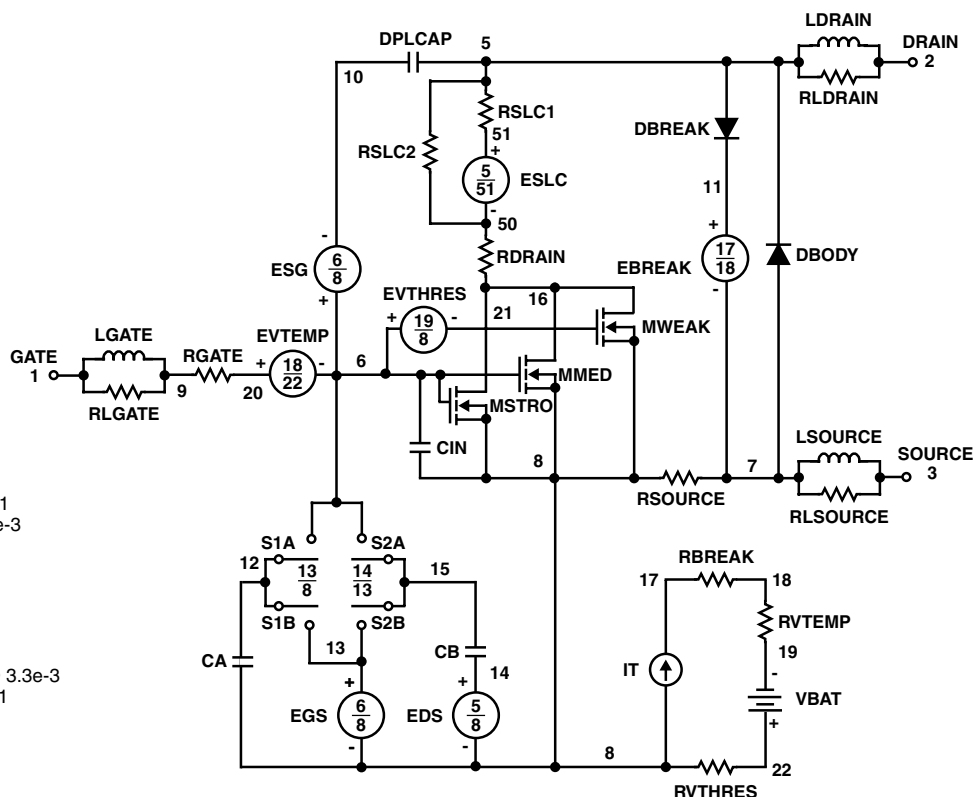


FIGURE 19. SWITCHING TIME WAVEFORM



SABER Electrical Model

REV 15 Feb 00

template huf75542p3 n2,n1,n3
electrical n2,n1,n3

```
{
var i iscl
dp..model dbodymod = (is = 2.5e-12, rs = 2.85e-3, xti = 5.5, trs1 = 2e-3, trs2 = 1e-6, cjo = 3.2e-9, tt = 5.5e-8, m = 0.6)
dp..model dbreakmod = (rs = 2.9e-1, trs1 = 1e-3, trs2 = 1e-6)
dp..model dplcapmod = (cjo = 3.4e-9, is = 1e-30, m = 0.8, nl = 10)
m..model mmedmod = (type=_n, vto = 3.06, kp = 4.8, is = 1e-30, tox = 1)
m..model mstrongmod = (type=_n, vto = 3.5, kp = 80, is = 1e-30, tox = 1)
m..model mwweakmod = (type=_n, vto = 2.67, kp = 0.08, is = 1e-30, tox = 1)
sw_vcsp..model s1amod = (ron = 1e-5, roff = 0.1, von = -6.0, voff = -4.5)
sw_vcsp..model s1bmod = (ron = 1e-5, roff = 0.1, von = -4.5, voff = -6.0)
sw_vcsp..model s2amod = (ron = 1e-5, roff = 0.1, von = -0.5, voff = 0.5)
sw_vcsp..model s2bmod = (ron = 1e-5, roff = 0.1, von = 0.5, voff = -0.5)
```

```
c.ca n12 n8 = 4.4e-9
c.cb n15 n14 = 4.2e-9
c.cin n6 n8 = 2.5e-9
dp.dbody n7 n5 = model=dbodymod
dp.dbreak n5 n11 = model=dbreakmod
dp.dplcap n10 n5 = model=dplcapmod
```

i.it n8 n17 = 1

```
l.ldrain n2 n5 = 1e-9
l.lgate n1 n9 = 2.6e-9
l.lsource n3 n7 = 1.1e-9
```

```
m.mmed n16 n6 n8 n8 = model=mmedmod, l=1u, w=1u
m.mstrong n16 n6 n8 n8 = model=msstrongmod, l=1u, w=1u
m.mweak n16 n21 n8 n8 = model=mwweakmod, l=1u, w=1u
```

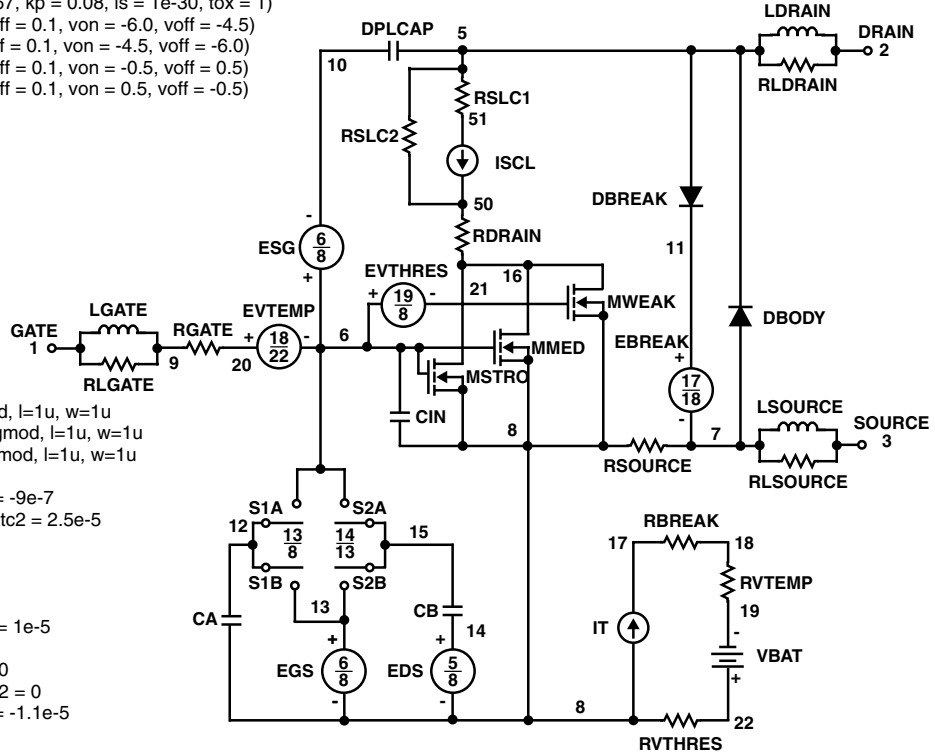
```
res.rbreak n17 n18 = 1, tc1 = 1.3e-3, tc2 = -9e-7
res.rdrain n50 n16 = 5.5e-3, tc1 = 1.1e-2, tc2 = 2.5e-5
res.rgate n9 n20 = 1.0
res.rldrain n2 n5 = 10
res.rlgate n1 n9 = 26
res.rlsource n3 n7 = 11
res.rslc1 n5 n51 = 1e-6, tc1 = 4.5e-3, tc2 = 1e-5
res.rslc2 n5 n50 = 1e3
res.rsource n8 n7 = 3.3e-3, tc1 = 0, tc2 = 0
res.rvtemp n18 n19 = 1, tc1 = -2.75e-3, tc2 = 0
res.rvthres n22 n8 = 1, tc1 = -2.5e-3, tc2 = -1.1e-5
```

```
spe.ebreak n11 n7 n17 n18 = 87.2
spe.eds n14 n8 n5 n8 = 1
spe.egs n13 n8 n6 n8 = 1
spe.esg n6 n10 n6 n8 = 1
spe.evtemp n20 n6 n18 n22 = 1
spe.evthres n6 n21 n19 n8 = 1
```

```
sw_vcsp.s1a n6 n12 n13 n8 = model=s1amod
sw_vcsp.s1b n13 n12 n13 n8 = model=s1bmod
sw_vcsp.s2a n6 n15 n14 n13 = model=s2amod
sw_vcsp.s2b n13 n15 n14 n13 = model=s2bmod
```

v.vbat n22 n19 = dc=1

```
equations {
i (n51->n50) +=iscl
iscl: v(n51,n50) = ((v(n5,n51)/(1e-9+abs(v(n5,n51))))*((abs(v(n5,n51)*1e6/230))** 2.5))
}
}
```



SPICE Thermal Model

REV 15 Feb 00

T75542

CTHERM1 th 6 4.1e-3
 CHERM2 6 5 5.5e-3
 CHERM3 5 4 8.6e-3
 CHERM4 4 3 1.5e-2
 CHERM5 3 2 1.6e-2
 CHERM6 2 tl 6.5e-2

RHERM1 th 6 2.0e-4
 RHERM2 6 5 3.5e-3
 RHERM3 5 4 2.5e-2
 RHERM4 4 3 9.0e-2
 RHERM5 3 2 1.6e-1
 RHERM6 2 tl 2.3e-1

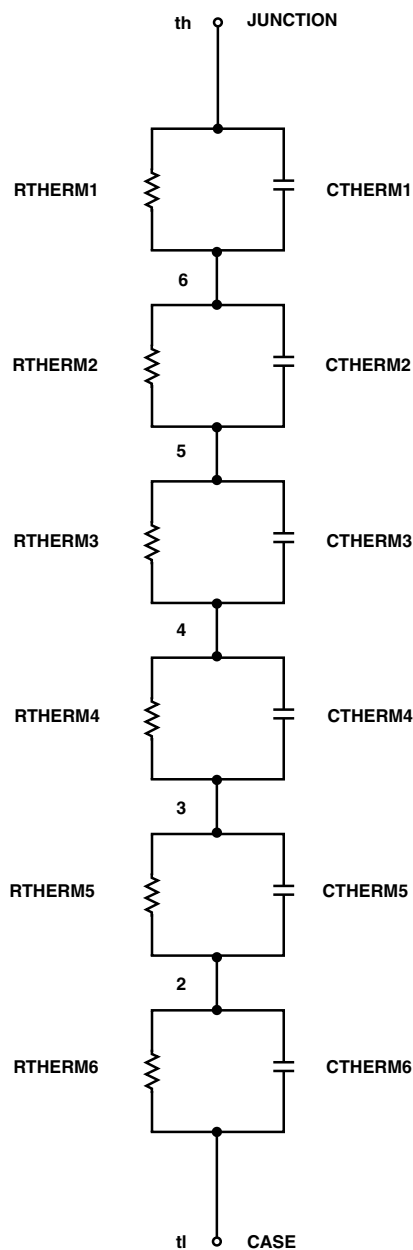
SABER Thermal Model

SABER thermal model t75542

template thermal_model th tl
 thermal_c th, tl

```
{
    ctherm.ctherm1 th 6 = 4.1e-3
    ctherm.ctherm2 6 5 = 5.5e-3
    ctherm.ctherm3 5 4 = 8.6e-3
    ctherm.ctherm4 4 3 = 1.5e-2
    ctherm.ctherm5 3 2 = 1.6e-2
    ctherm.ctherm6 2 tl = 6.5e-2
```

```
rtherm.rtherm1 th 6 = 2.0e-4
rtherm.rtherm2 6 5 = 3.5e-3
rtherm.rtherm3 5 4 = 2.5e-2
rtherm.rtherm4 4 3 = 9.0e-2
rtherm.rtherm5 3 2 = 1.6e-1
rtherm.rtherm6 2 tl = 2.3e-1
}
```



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CoolFET™	GlobalOptoisolator™	PowerTrench [®]	SuperSOT™-8
CROSSVOLT™	GTO™	QFET™	SyncFET™
DenseTrench™	HiSeC™	QS™	TinyLogic™
DOME™	ISOPLANAR™	QT Optoelectronics™	UHC™
EcoSPARK™	LittleFET™	Quiet Series™	UltraFET™
E ² CMOS™	MicroFET™	SILENT SWITCHER [®]	VCX™
EnSigna™	MICROWIRE™	SMART START™	
FACT™	OPTOLOGIC™	Star* Power™	
FACT Quiet Series™	OPTOPLANAR™	Stealth™	

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2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

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Definition of Terms

Datasheet Identification	Product Status	Definition
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Preliminary	First Production	This datasheet contains preliminary data, and supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
No Identification Needed	Full Production	This datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
Obsolete	Not In Production	This datasheet contains specifications on a product that has been discontinued by Fairchild semiconductor. The datasheet is printed for reference information only.